

**Notice of References Cited**

Application/Control No.

09/992,624

Applicant(s)/Patent Under  
Reexamination  
HIEW ET AL.

Examiner

Fred Ferris

Art Unit

2128

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	X	"Using a Fine-Grained Comparative Evaluation Technique to Understand and Design Software Visualization Tools", Mulholland, Seventh workshop on Empirical studies of programmers, ACM 1997

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.